Customers

- Charles University in Prague, Group of Surface Science
- Materials Science Beamline, Synchrotron Elettra, Trieste, Italy
- Academy of Sciences of the Czech Republic, Prague
- National Institute for Materials Science Tsukuba, Japan
- Synchrotron SPring-8, Sayo, Japan
- *other Japan institutes and companies*: Meiji University, Kyushu University, Kyoto University, LEAP, Gene & Coherent Technologies, Nakayama Corporation
- Heinrich-Heine-Universität Düsseldorf, Germany
- Lehrstuhl fuer Physikalische Chemie II, Friedrich-Alexander-Universitaet Erlangen-Nuernberg
- Department of Solid State Physics, University of Lodz, Poland
- Department of Physics, University of California at Davis, USA
- ALS Synchtrotron, Lawrence Berkeley National Laboratory, Berkeley, USA
- Chonbuk National University, Jeonju, South Korea
- etc...

Some papers where KolXPD was used

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